



APPROVAL SHEET

Approval Specification	Customer's Approval Certificate
<p>TO:</p> <p>Part No.:</p> <p>Customer's Part No.:</p>	<p>Please return this copy as a certification of your approval</p> <p>Checked & Approved by:</p> <p>Date:</p>

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Part No.	:	SF0363
Pages	:	6
Date	:	2014/05/22
Revision	:	1.0

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Checked by:	
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Performance**Maximum Rating**

Item		Value	Unit
DC Voltage	V_{DC}	3	V
Operation Temperature	T	-45 ~ +85	°C
Storage Temperature	T_{stg}	-55 ~ +125	°C
RF Power Dissipation	P	10	dBm

Electronic Characteristics

Test Temperature: $25^{\circ}\text{C} \pm 2^{\circ}\text{C}$

Terminating source impedance: 50Ω

Terminating load impedance: 50Ω

Item		Minimum	Typical	Maximum	Unit
Center Frequency	f_c	69.9	70.0	70.1	MHz
Insertion Loss	69.00-71.00 MHz IL		10.0	15.0	dB
Amplitude Ripple	$\Delta\alpha$		0.6	1.0	dB
1 dB Bandwidth	BW_{1dB}	2.0	2.4		MHz
40 dB Bandwidth	BW_{40dB}		5.8	6.0	MHz
Group Delay Ripple	69.00-71.00 MHz GDR		150.0	200.0	ns
Absolute Attenuation	α				
	DC-66.00 MHz	40.0	42.0		dB
	74.00-100.00 MHz	40.0	45.0		dB
Input VSWR	69.00-71.00 MHz		1.5:1	2.5:1	/
Output VSWR	69.00-71.00 MHz		1.5:1	2.5:1	/

Notes

1. As a result of the particularity of inner structure of SAW products, it easy to be breakdown by electrostatic, so we should pay attention to **ESD protect** in the test.
2. **Static voltage** between signal load and ground may cause deterioration and destruction of the component. Please avoid static voltage.
3. **Ultrasonic cleaning** may cause deterioration and destruction of the component. Please avoid ultrasonic cleaning.
4. Only leads of component may **be soldered**. Please avoid soldering another part of component.
5. There is a close relationship between the device's performance and **matching network**. The specifications of this device are based on the test circuit shown above. L and C values may change depending on board layout. Values shown are intended as a guide only.